

Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter	Max ratings	Unit
V _{DSS}	Drain - Source Voltage	1200	V
I _D	Continuous Drain Current	T _c = 25°C	78
		T _c = 80°C	58
I _{DM}	Pulsed Drain current	155	A
V _{GS}	Gate - Source Voltage	-10/25V	V
R _{DS(on)}	Drain - Source ON Resistance	33	mΩ
P _D	Maximum Power Dissipation	T _c = 25°C	370
			W

Electrical Characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
I _{DSS}	Zero Gate Voltage Drain Current	V _{GS} = 0V, V _{DS} = 1200V			300	μA
R _{DS(on)}	Drain - Source on Resistance	V _{GS} = 20V I _D = 60A	T _j = 25°C	27	33	mΩ
			T _j = 150°C	50	70	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} = V _{DS} , I _D = 3mA	1.7	2.2		V
I _{GSS}	Gate - Source Leakage Current	V _{GS} = 20V, V _{DS} = 0V			750	nA

Dynamic Characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
C _{iss}	Input Capacitance	V _{GS} = 0V V _{DS} = 1000V f = 1MHz		2.85		nF
C _{oss}	Output Capacitance			0.24		
C _{rss}	Reverse Transfer Capacitance			0.02		
Q _g	Total gate Charge	V _{GS} = 0/20V V _{Bus} = 800V I _D = 60A		148		nC
Q _{gs}	Gate - Source Charge			32		
Q _{gd}	Gate - Drain Charge			54		
T _{d(on)}	Turn-on Delay Time	V _{GS} = -5/+20V V _{Bus} = 800V I _D = 60A, T _j = 150°C R _L = 13Ω ; R _{Gext} = 16.7Ω		20		ns
T _r	Rise Time			20		
T _{d(off)}	Turn-off Delay Time			75		
T _f	Fall Time			35		
E _{on}	Turn on Energy	Inductive Switching V _{GS} = -5/+20V V _{Bus} = 600V I _D = 60A R _{Gext} = 16.7Ω	T _j = 150°C	1.3		mJ
E _{off}	Turn off Energy			T _j = 150°C	0.7	
R _{Gint}	Internal gate resistance			3.2		Ω
R _{thJC}	Junction to Case Thermal Resistance				0.34	°C/W

Source - Drain diode ratings and characteristics (per SiC MOSFET)

Symbol	Characteristic	Test Conditions	Min	Typ	Max	Unit
V _{SD}	Diode Forward Voltage	V _{GS} = -5V, I _{SD} = 30A		3.3		V
		V _{GS} = -2V, I _{SD} = 30A		3.1		
t _{rr}	Reverse Recovery Time	I _{SD} = 60A ; V _{GS} = -5V V _R = 800V ; di _F /dt = 1000A/μs		40		ns
Q _{rr}	Reverse Recovery Charge			415		nC
I _{rr}	Reverse Recovery Current			20		A

SiC schottky diode ratings and characteristics (per SiC diode)

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>		<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
V _{RRM}	Peak Repetitive Reverse Voltage					1200	V
I _{RRM}	Reverse Leakage Current	V _R =1200V	T _j = 25°C		100	600	μA
			T _j = 175°C		170	3000	
I _F	DC Forward Current		T _C = 125°C		30		A
V _F	Diode Forward Voltage	I _F = 30A	T _j = 25°C		1.6	1.8	V
			T _j = 175°C		2.3	3	
Q _C	Total Capacitive Charge	I _F = 30A, V _R = 1200V di/dt = 1200A/μs			240		nC
C	Total Capacitance	f = 1MHz, V _R = 200V			288		pF
		f = 1MHz, V _R = 400V			207		
R _{thJC}	Junction to Case Thermal Resistance					0.37	°C/W

Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

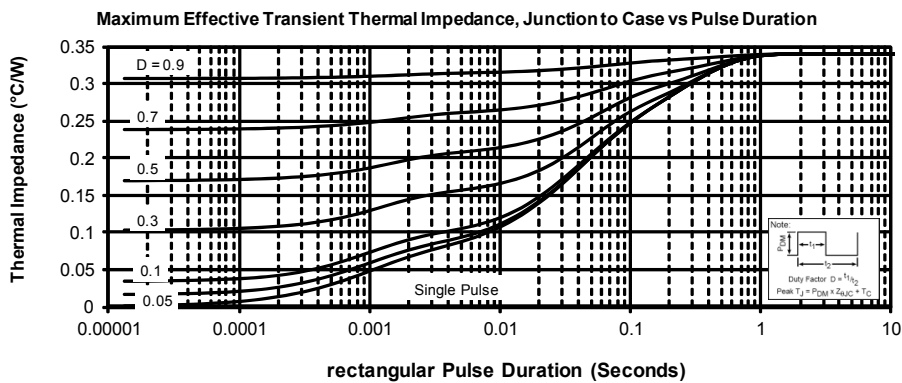
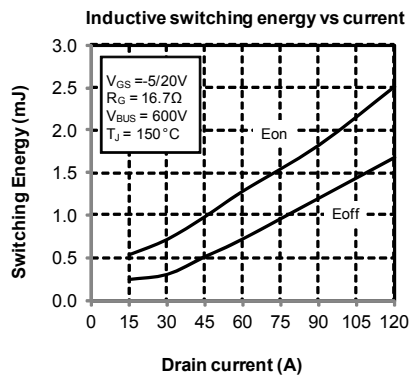
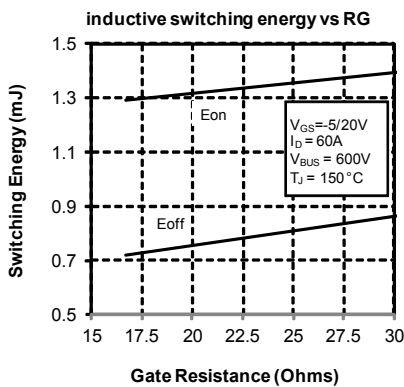
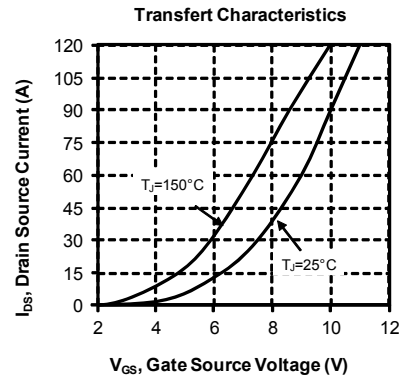
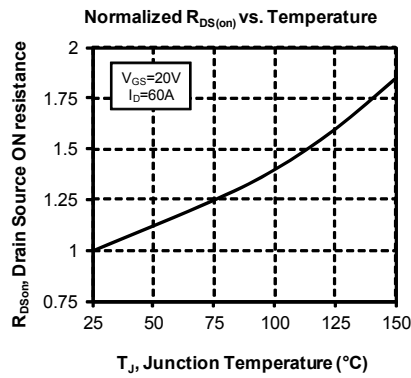
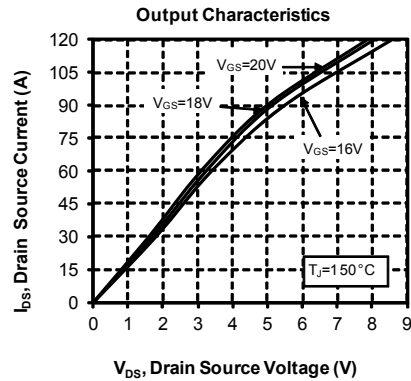
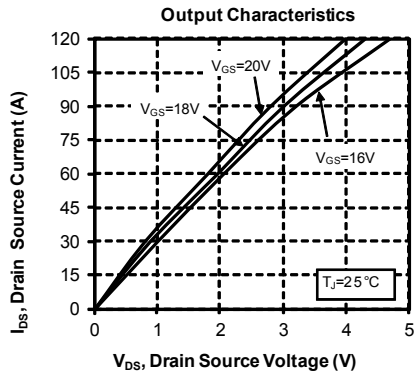
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R ₂₅	Resistance @ 25°C		50		kΩ
ΔR ₂₅ /R ₂₅			5		%
B _{25/85}	T ₂₅ = 298.15 K		3952		K
ΔB/B			4		%

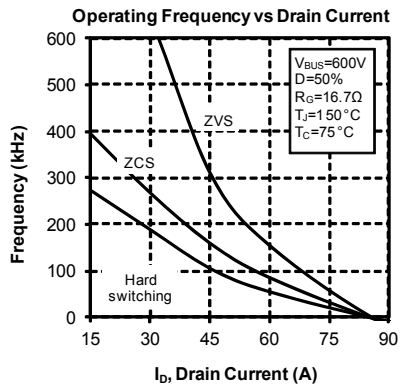
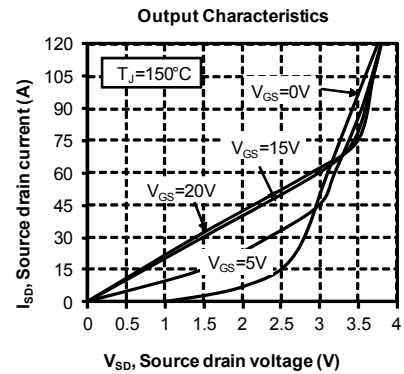
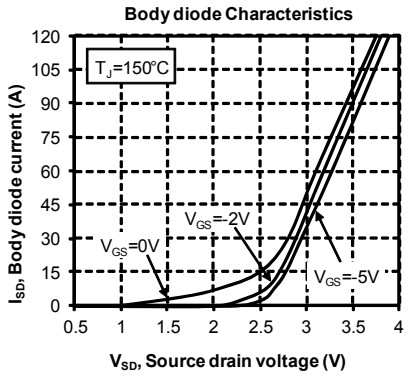
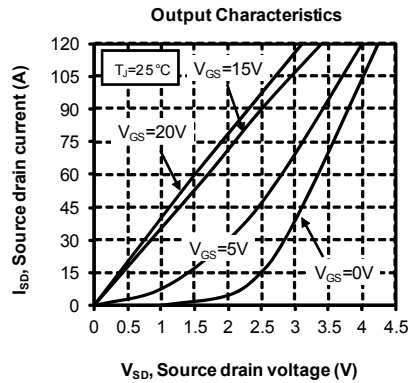
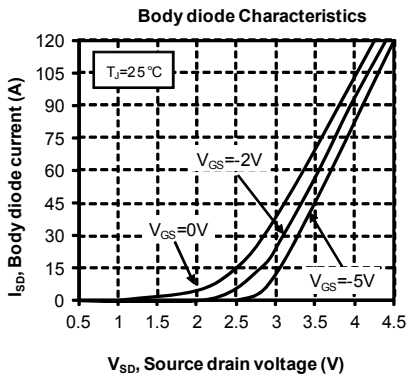
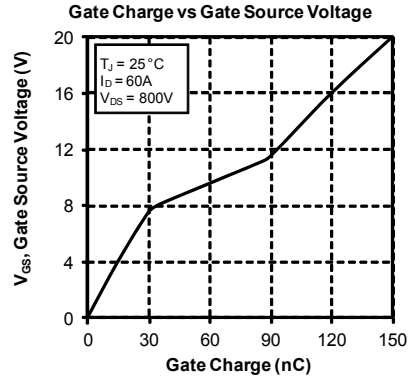
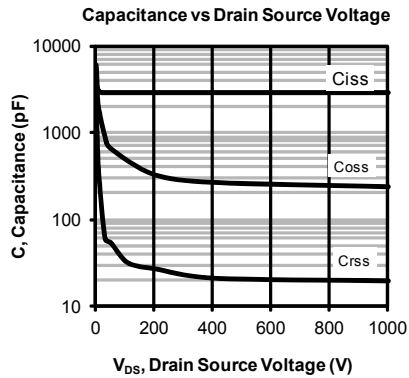
$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$

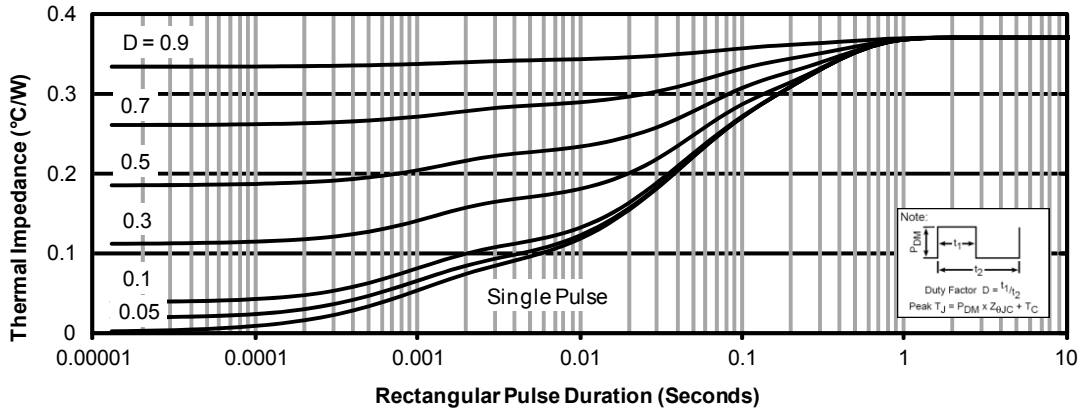
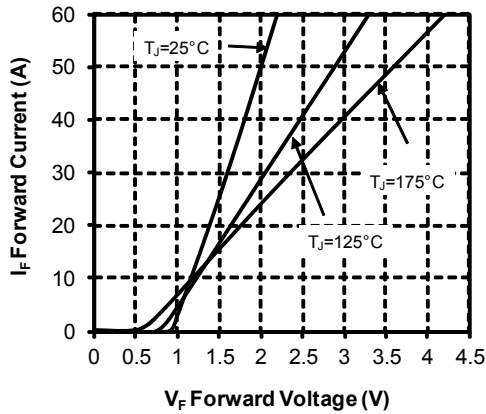
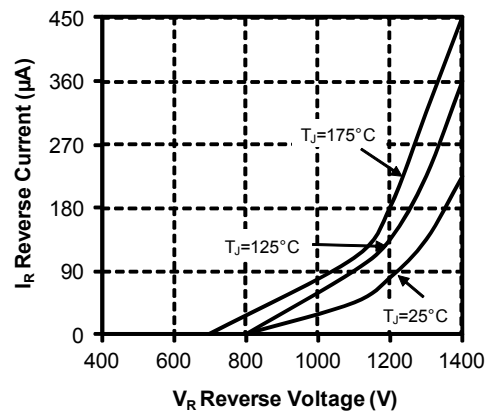
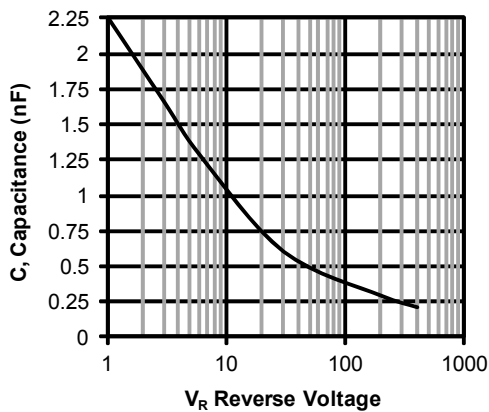
T: Thermistor temperature
R_T: Thermistor value at T

Thermal and package characteristics

<i>Symbol</i>	<i>Characteristic</i>	<i>Min</i>	<i>Max</i>	<i>Unit</i>		
V _{ISOL}	RMS Isolation Voltage, any terminal to case t = 1 min, 50/60Hz	4000		V		
T _J	Operating junction temperature range	SiC MOSFET	-40	150	°C	
		SiC diode	-40	175		
T _{JOP}	Recommended junction temperature under switching conditions	-40	T _{Jmax} -25			
T _{STG}	Storage Temperature Range	-40	125			
T _C	Operating Case Temperature	-40	100			
Torque	Mounting torque	To heatsink	M6	3	5	N.m
Wt	Package Weight				250	g

Typical SiC MOSFET Performance Curve




Typical SiC diode Performance Curve
Maximum Effective Transient Thermal Impedance, Junction to Case vs Pulse Duration

Forward Characteristics

Reverse Characteristics

Capacitance vs. Reverse Voltage




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